

NOT RECOMMENDED FOR NEW DESIGN **NO ALTERNATE PART**

HTMN5130SSD



55V DUAL N-CHANNEL 175°C MOSFET

Product Summary

V _{(BR)DSS}	R _{DS(on) max}	I _D T _A = +25°C
55V	$130m\Omega$ @ $V_{GS} = 10V$	2.86 A
	$200m\Omega$ @ $V_{GS} = 4.5V$	2.3 A

Description

This new generation MOSFET has been designed to minimize the onstate resistance (R_{DS(ON)}) and yet maintain superior switching performance, making it ideal for high efficiency power management applications.

Applications

- DC-DC Converters
- **Power Management Functions**
- Backlighting

Features and Benefits

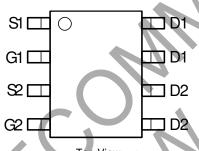
- Low Input Capacitance
- Low On-Resistance
- Fast Switching Speed
- Totally Lead-Free & Fully RoHS Compliant (Notes 1 & 2)
- Halogen and Antimony Free. "Green" Device (Note 3)
- Qualified to AEC-Q101 Standards for High Reliability

Mechanical Data

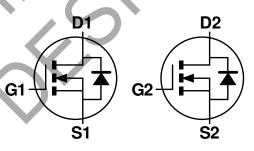
- Case: SO-8
- Case Material: Molded Plastic, "Green" Molding Compound. UL Flammability Classification Rating 94V-0
- Moisture Sensitivity: Level 1 per J-STD-020
- Terminal Connections: See Diagram
- Terminals: Finish Tin Finish annealed over Copper leadframe. Solderable per MIL-STD-202, Method 208 (e3)
- Weight: 0.074 grams (approximate)



Top View



Top View Pin Configuration



Equivalent Circuit

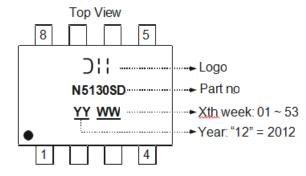
Ordering Information (Note 4)

Part Number	Case	Packaging
HTMN5130SSD-13	SO-8	2,500/Tape & Reel

Notes:

- 1. No purposely added lead. Fully EU Directive 2002/95/EC (RoHS) & 2011/65/EU (RoHS 2) compliant.
- 2. See http://www.diodes.com/quality/lead_free.html for more information about Diodes Incorporated's definitions of Halogen- and Antimony-free, "Green" and Lead-free
- 3. Halogen- and Antimony-free "Green" products are defined as those which contain <900ppm bromine, <900ppm chlorine (<1500ppm total Br + Cl) and <1000ppm antimony compounds.
 4. For packaging details, go to our website at http://www.diodes.com/products/packages.html.

Marking Information





Maximum Ratings (@T_A = +25°C, unless otherwise specified.)

Characteristic	Symbol	Value	Units		
Drain-Source Voltage	V _{DSS}	55	V		
Gate-Source Voltage			V _{GSS}	±20	V
	Steady State	T _A = +25°C	I _D	2.6	А
Continuous Drain Current (Note 6) V _{GS} = 10V	t<10s	$T_A = +25$ °C $T_A = +70$ °C	I _D	2.86 2.3	А
Pulsed Drain Current (10µs pulse, duty cycle = 1%)	I _{DM}	8	А		
Continuous Source Current (Body Diode) (Note 6)			Is	2.8	Α
Pulsed Source Current (Body Diode)			I _{SM}	8	А
Avalanche Current (Note 5) L =4.9mH			I _{AS}	6	Α
Avalanche Energy (Note 5) L = 4.9mH			Eas	89	mJ

Thermal Characteristics (@T_A = +25°C, unless otherwise specified.)

Characteristic		Symbol	Value	Units
Total Power Dissipation (Note 6)	$T_A = +25^{\circ}C$ $T_A = +70^{\circ}C$	P _D	1.7 1.1	W
Thermal Resistance, Junction to Ambient (Note 6)	Steady state t<10s	R _{0JA}	72 50	°C/W
Thermal Resistance, Junction to Case (Note 6)		Rejc	11.2	
Operating and Storage Temperature Range		T _J , T _{STG}	-55 to +175	°C

Electrical Characteristics (@TA = +25°C, unless otherwise specified.)

Characteristic	Symbol	Min	Тур	Max	Unit	Test Condition	
OFF CHARACTERISTICS (Note 7)	O,bo.		- 76	III.da	O	1001 00114111011	
Drain-Source Breakdown Voltage	BV _{DSS}	55			V	V _{GS} = 0V, I _D = 250μA	
Zero Gate Voltage Drain Current	IDSS	_	74	100	nA	V _{DS} = 55V, V _{GS} = 0V	
Gate-Source Leakage	I _{GSS}		\ _	±100	nA	$V_{GS} = \pm 20V, V_{DS} = 0V$	
ON CHARACTERISTICS (Note 7)							
Gate Threshold Voltage	V _{GS(th)}	1	_	3	V	$V_{DS} = V_{GS}$, $I_D = 250\mu A$	
Static Drain-Source On-Resistance	Prevent		_	130	mΩ	V _{GS} = 10V, I _D = 3 A	
Static Drain-Source On-nesistance	R _{DS(ON)}	_	_	200	11122	$V_{GS} = 4.5V, I_D = 1.5A$	
Diode Forward Voltage	V _{SD}		_	1.0	V	V _{GS} = 0V, I _S = 1.5A	
DYNAMIC CHARACTERISTICS (Note 8)							
Input Capacitance	C _{iss}	_	218.7	_		V _{DS} = 25V, V _{GS} = 0V f = 1.0MHz	
Output Capacitance	Coss	_	97.8	_	pF		
Reverse Transfer Capacitance	C _{rss}	_	22.4	_			
Gate Resistance	R _G	_	3.75	_	Ω	$V_{DS} = 0V$, $V_{GS} = 0V$, $f = 1.0MHz$	
Total Gate Charge (V _{GS} = 10V)	Qg	_	8.9	_			
Total Gate Charge (V _{GS} = 4.5V)	Q_g	_	4.7	_	nC	$V_{DS} = 40V, I_{D} = 2A$	
Gate-Source Charge	Qgs	_	1.0	_	110	VDS = 40 V, ID = 2A	
Gate-Drain Charge	Q_{gd}	_	2.9	_			
Turn-On Delay Time	t _{D(on)}	_	3	_		$V_{GS} = 10V, V_{DD} = 25V, R_G = 6\Omega,$	
Turn-On Rise Time	t _r	_	2.5	_	nS		
Turn-Off Delay Time	t _{D(off)}	_	13.5	_	113	I _D = 1A	
Turn-Off Fall Time	t _f	_	6.1	_			
Body Diode Reverse Recovery Time	t _{rr}		30.8		nS	I _F = 1.5A, dI/dt = 100A/μs	
Body Diode Reverse Recovery Charge	Q _{rr}	_	35.4	_	nC	I _F = 1.5A, dI/dt = 100A/μs	

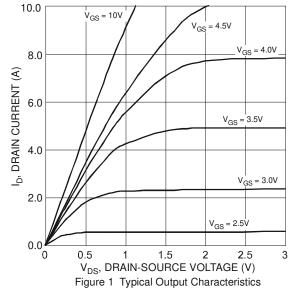
Notes: 5. I_{AR} and E_{AR} rating are based on low frequency and duty cycles to keep $T_J = +25$ °C.

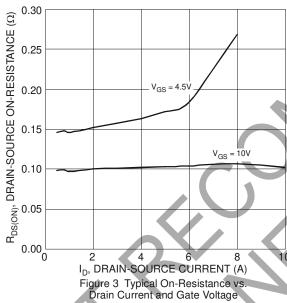
^{6.} Device mounted on FR-4 substrate PC board, 2oz copper, with 1inch square copper plate.

^{7.} Short duration pulse test used to minimize self-heating effect.

^{8.} Guaranteed by design. Not subject to product testing.







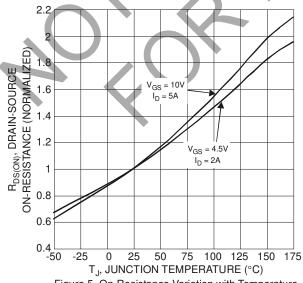
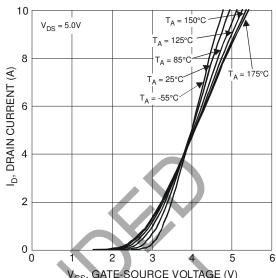


Figure 5 On-Resistance Variation with Temperature



 $V_{\rm GS},$ GATE-SOURCE VOLTAGE (V) Figure 2 Typical Transfer Characteristics

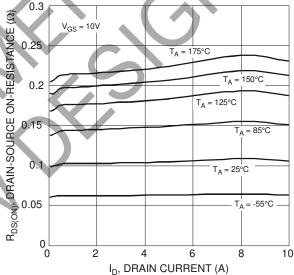


Figure 4 Typical On-Resistance vs. Drain Current and Temperature

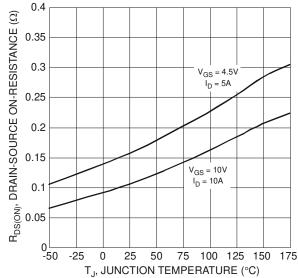


Figure 6 On-Resistance Variation with Temperature



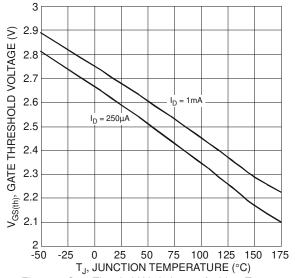
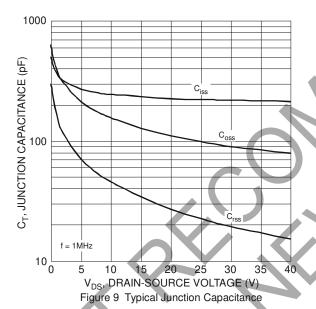
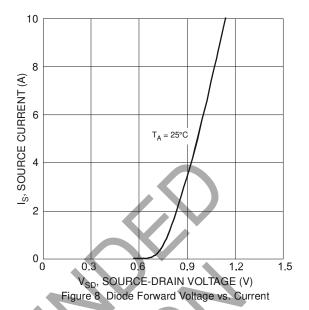
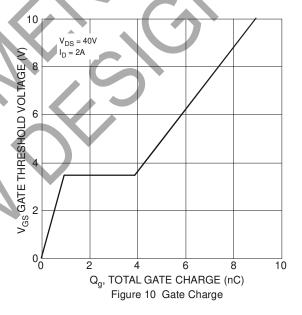


Figure 7 Gate Threshold Variation vs. Ambient Temperature

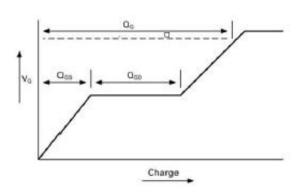


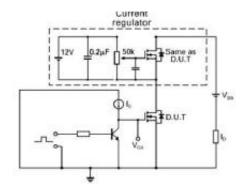






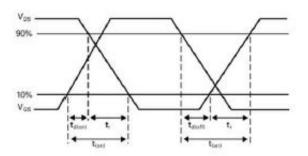
Test Circuits

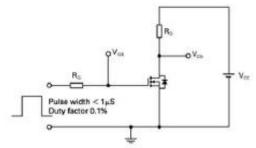




Basic gate charge waveform

Gate charge test circuit



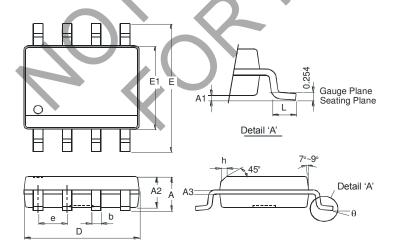


Switching time waveforms

Switching time test circuit

Package Outline Dimensions

Please see AP02002 at http://www.diodes.com/datasheets/ap02002.pdf for latest version.

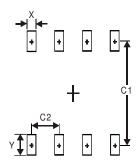


SO-8					
Dim	Min	Max			
Α	-	1.75			
A1	0.10	0.20			
A2	1.30	1.50			
A3	0.15	0.25			
q	0.3	0.5			
D	4.85	4.95			
Е	5.90	6.10			
E1	3.85	3.95			
е	1.27 Typ				
h	-	0.35			
L	0.62	0.82			
θ	0°	8°			
All Dimensions in mm					



Suggested Pad Layout

Please see AP02001 at http://www.diodes.com/datasheets/ap02001.pdf for the latest version.



Dimensions	Value (in mm)
X	0.60
Υ	1.55
C1	5.4
C2	1.27

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